

Notice of References Cited	Application/Control No. 10/566,828	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
	Examiner Ryan Lepisto	Art Unit 2883	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0057868	05-2002	Wu et al.	385/24
*	B	US-4,569,569	02-1986	Stewart, William J.	385/36
*	C	US-2003/0081885	05-2003	Chen et al.	385/18
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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